

HQ:CSC38/No Al

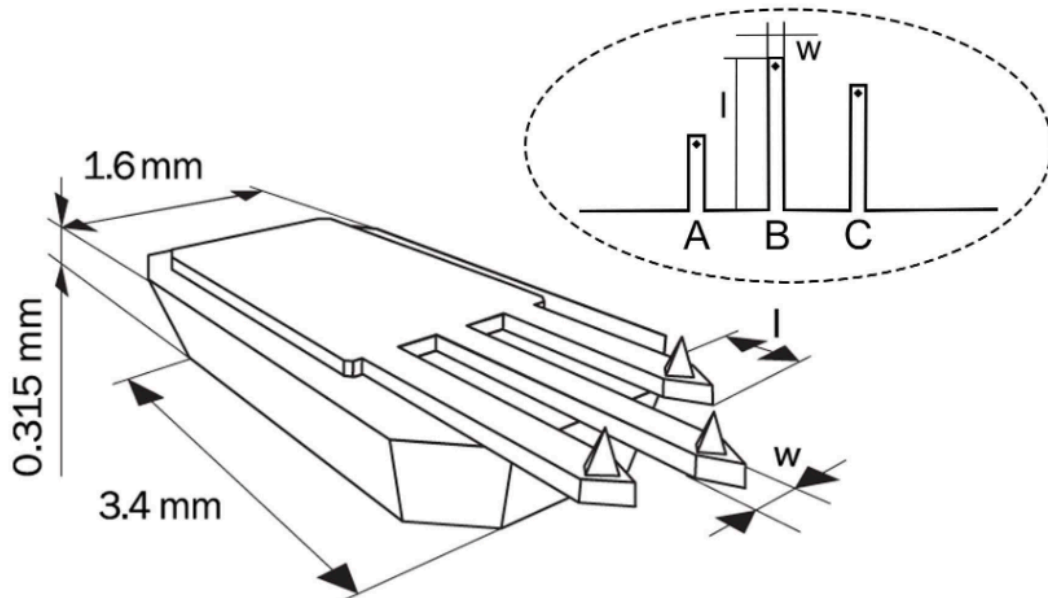
AFM Probe with 3 Different Contact Mode AFM Cantilevers

AFM probes of the HQ:CSC38 series have three different soft contact mode AFM cantilevers on one side of the holder chip. They can be used in various applications.

The HQ AFM probes offer high consistency of the AFM tip radius, the AFM cantilever reflectivity and the quality factor.

Coating

none



AFM Probe Specifications

AFM Tip

SHAPE	HEIGHT	FULL CONE ANGLE	RADIUS
Rotated	15 μm (12 – 18 μm)*	40°	< 8 nm

AFM Cantilever

CANTILEVER	SHAPE	FORCE CONST.	RES. FREQ.	LENGTH	WIDTH	THICKNESS
Cantilever A	Beam	0.09 N/m (0.01 – 0.36 N/m)*	20 kHz (8 – 32 kHz)*	250 μm (1 – 255 μm)*	32.5 μm (29.5 – 35.5 μm)*	1 μm (0.5 – 1.5 μm)*
Cantilever B	Beam	0.03 N/m (0.003 – 0.13 N/m)*	10 kHz (5 – 17 kHz)*	350 μm (1 – 355 μm)*	32.5 μm (29.5 – 35.5 μm)*	1 μm (0.5 – 1.5 μm)*
Cantilever C	Beam	0.05 N/m (0.005 – 0.21 N/m)*	14 kHz (6 – 23 kHz)*	300 μm (1 – 305 μm)*	32.5 μm (29.5 – 35.5 μm)*	1 μm (0.5 – 1.5 μm)*

* typical values